Abstract

Method and Device For Detecting Defects In An Object

Method for detecting defects (22) in an object (20) comprising the steps of locally illuminating (10) the object (20) by radiating in light (50) having a wavelength to which the object (20) is transparent, detecting (12) multiply reflected components of the incident light (50) whilst at least partly avoiding the detection of directly transmitted components (48) of the incident light and at least partly avoiding the detection of singly reflected components (53a, 53b) of the incident light (50), and identifying (14) defects (22) by evaluating intensity differences in the detected components of the incident light (50), and device for carrying out the method.

Figure 5